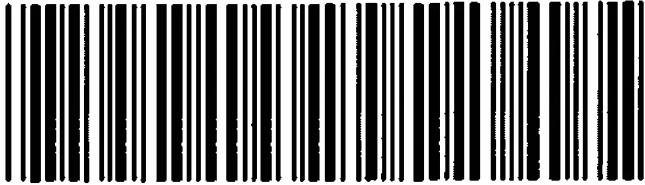


<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>	
	10/618,036	TEH ET AL.	
	<b>Examiner</b>	<b>Art Unit</b>	
	Leon J. Harper	2166	

SEARCHED			
Class	Subclass	Date	Examiner
707	104.1, 200, 100, 1	12/21/2005	LJH

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
consulted with L. wassumm about scope of art	12/20/2005	LJH